

<b>Notice of References Cited</b>	Application/Control No. 10/722,907	Applicant(s)/Patent Under Reexamination TANADA ET AL.	
	Examiner (Nancy) Thanh-Nhan P Nguyen	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0007113	01-2003	Yamanaka et al.	349/113
	B	US-6,434,815	08-2002	Onishi et al.	29/621
	C	US-6,610,766	08-2003	Kitamura et al.	524/156
	D	US-6,699,956	03-2004	Kudo et al.	528/15
	E	US-2003/0194646	10-2003	Ogiso et al.	430/270.16
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP4011149241A	06-1989	Japan	Tanii et al	428/412; 428/422
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.